

CCD PERFORMANCE

System Overview

Description	Model					Se	rial Number	
CCD Head V	D U 9	34P	-	BR-DI	C	CC	D-17880	
TE Cooler performance (•)				High		Ultra-high	•
Accessories	Power Su	oply Un	it (PS -2	4)			PS -25	5
							*	
S	SO-	LM-			MFL	-		
Serial/Batch Number								Contrast of
Other								
V Sensor types are	defined in Tak	ole 1 usin	g the last	two lette	ers in b	ox Mo	odel Number.	

Sensor types are defined in Table 1 using the last two letters in box Model Number.

CCD Details

Manufac	turer / Model No.	Pixels S	Serial Number
E2V	CCD47-10	1024x1024, 13μm x 13μm	12262-06-08
E2V	CCD57-10	512x512, (FT), 13μm x 13μm	
E2V	CCD77-00	512x512, 24µm x 24µm	

Special Feature	(🗸)	(🗸)
NIMO	Custom Mount	ting Flange
Fringe Suppression	Custom Cable	S
Shielded Anti-Blooming		

Window Variant	(🗸)	(🖌)
VUV-UV Parallel	NUV-Enhanced Parallel	
Broadband VUV-NIR Wedged	Broadband VUV-NIR Parallel	
Broadband VIS-NIR Wedged	Broadband VIS-NIR Parallel	~
VIS-NIR Enhanced Wedged	Bose-Einstein 780nm Wedged	
None	Other	

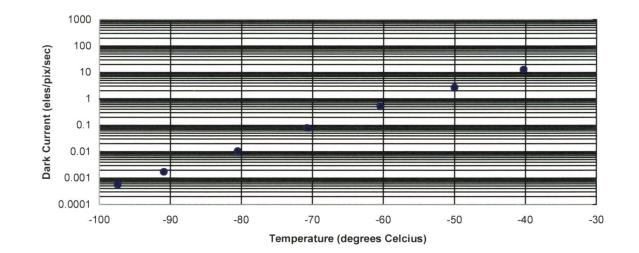


Summary of System Test Data

Readout Noise +1 and Base Mean Level

A/D Rate	Preamp	CCD	Single Pixel	Full Vert Bin	Base Level #2
(MHz All 16 bit)	setting	Sensitivity +3	Noise	Noise	(Counts)
		eles per A/D count	electrons	electrons	
5	x1	7.1	36.6	36.0	942
5	x2	3.5	20.3	20.6	1559
5	x4	1.7	14.4	15.4	2805
3	x1	6.1	20.0	19.9	1052
3	x2	3.1	13.1	13.5	1944
3	x4	1.4	11.2	10.8	3608
1	x1	5.3	11.3	10.8	854
1	x2	2.7	8.1	7.9	1739
1	x4	1.3	6.6	6.5	3573
0.05	x1	5.3	5.3	5.3	536
0.05	x2	2.8	4.3	4.4	1394
0.05	x4	1.3	3.7	3.7	3173
Satura	tion Signal p	er pixel	140609	Electror	is/pixel

CCD Dark Current



Minimum Dark Current Achievable •4	0.000562	electro	ons/pixel/s	ес
@ Sensor Temperature of +5	-97.419	°C	16	°C cooling Water
		With PS	-25	
CCD Dark Current Uniformity better than +6	0.3763	electro	ons/pixel/s	ec



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Linearity and Uniformity

Linearity better than •7	1	% over 16 bits
Response Uniformity better than <a>8	1.87	%

Response Defects

White/Black Spots +	9			(X,Y)
Centroid	Number of Pixels	Centroid	1	Number of Pixels
(X,X) (,,) (,,) (,,) (,,) (,,) (,)	X	(, (, (, (,)))))))	
White/Black Columns ♦10	Column num	bers indicated	X X	X X
Trap ♦11		(X,Y)	(X	, X)

Dark Current Defects

Centroid	Number of Pixels	Centroid	Number of Pixels
X, X)	X	(,)	
,)		()	
,)		(,)	
,)		(,) ()	
, ,)		(,)	



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Test Conditions

Readout Noise tested at	-80	°C with	16	°C water	
Base Mean Level measured at	-80	$^{\circ}C$ with	16	°C water	
Dark Current Uniformity tested at	-65	°C with	16	°C water	
Blemishes tested at	-65	°C with	16	°C water	

Custom Testing

Signed

Date

K.MCDOWELL

4TH JUNE 2015

System Passed for Shipping

Hardware	HEADBOARD	FPGA
Version #	ZB	20.24
Shipping Software	SOLIS	SDK
Version #		
Testing Software	SOLIS	SDK
Version #	4.27.30001.0	2.99.33001.0

v Table 1; Key code to define the meanings of the last two letters in the Model Number

		Sensor Options	
OE	Open electrode	BU2	Back Illuminated (BI) + 250nm UV optimised
FI	Front illuminated (FI)	BU	BI + UV (350nm) optimised
UV	FI+UV coating	BV	BI + VIS (550nm) optimised)
FO	FI + Fibre optic	BR-DD	BI + NIR +deepdepletion
FI-DD	FI + deep depletion	BN	BI with no AR coating



Performance Notes

- Readout Noise is measured for both single pixel (SP) and fully vertically binned (FVB)
 with the CCD in darkness at temperature indicated and minimum exposure time.
 Noise values will change with pre-amplifier gain selection [PAG].
- ♦2 Average electronic DC offset for CCD in darkness at temperature indicated and minimum exposure time under dark conditions measured by single pixel (SP) for imaging systems and by (FVB) for spectroscopic systems.
- ♦3 Sensitivity is calculated in photoelectrons per A/D count from measurements of the Photon Transfer Curve.
- Dark current falls exponentially with temperature. However, for a given temperature
 the actual dark current can vary by more than an order of magnitude from device to
 device. The devices are specified in terms of minimum dark current achievable rather
 than minimum temperature.
- ♦5 Minimum temperature achieved for thermoelectric (TE) cooler set to maximum value with water cooling
- ♦6 RMS (root mean square) deviation of dark current for fully binned operation for spectroscopic cameras, or full resolution image for imaging cameras, under dark conditions at temperature indicated (pixel/column defects not included). This variation is mainly cosmetic since it is fully subtractable without significant loss of performance.
- 7 Linearity is measured from a plot of Counts vs. Signal over the 16 bit dynamic range. Linearity is expressed as a %age deviation from a straight line fit. This quantity is not measured on individual systems.
- RMS (root mean square) deviation from the average response of the CCD in full
 resolution image for imaging cameras, illuminated with uniform white light (defects
 not included).
- ♦9 White/black pixels have signals >25% above/below the average (25% contrast) with uniform illumination across the sensor.
- \bullet 10 A black column is defined as having ≥ 10 black pixels for imaging cameras.
- 11 Pixels which absorb charge as it is clocked through the defective area. When the light source is switched off, the signal from the trap appears to drop off more slowly than the signal from the surrounding pixels.
- 12 Hot spots are counted if they exhibit >50 times the maximum specified dark current at the test temperature indicated.
- A column is considered defective if >10 pixels are affected, or if the column exhibits
 >2 times the maximum specified dark current at the test temperature indicated.